

Report No.: SZEM170900945303

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SAR Evaluation Report

SZEM1709009453CR Application No.:

Applicant: i.am.plus, LLC

Address of Applicant: 10960 Wilshire Blvd., 5th Floor Los Angeles CA 90024, United States.

Manufacturer: i.am.plus, LLC

Address of Manufacturer: 10960 Wilshire Blvd., 5th Floor Los Angeles CA 90024, United States.

Shenzhen Grandsun Electronic Co., Ltd. Factory:

Pingdi Gaogiao Industry Zone, Longgang District, Shenzhen, China Address of Factory:

Equipment Under Test (EUT):

EUT Name: Bluetooth wireless earphones

Model No.: IMBT25 ♣

Please refer to section 4.1 of this report which indicates which model was

actually tested and which were electrically identical.

Trade mark:

FCC ID: 2AB2S-IMBT25 47 CFR Part 1.1307 Standards: 47 CFR Part 2.1093

KDB447498D01 General RF Exposure Guidance v06

Date of Receipt: 2017-09-05

Date of Test: 2017-09-08 to 2017-10-10

Date of Issue: 2017-10-12

Test Result: PASS*

In the configuration tested, the EUT complied with the standards specified above.



Jack Zhang **EMC Laboratory Manager**

The manufacturer should ensure that all products in series production are in conformity with the product sample detailed in this report. If the product in this report is used in any configuration other than that detailed in the report, the manufacturer must ensure the new system complies with all relevant standards. Any mention of SGS International Electrical Approvals or testing done by SGS International Electrical Approvals in connection with, distribution or use of the product described in this report must be approved by SGS International Electrical Approvals in writing.

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2 Version

Revision Record					
Version	Chapter	Date	Modifier	Remark	
01		2017-10-12		Original	

Authorized for issue by:		
	Moon-Zhang	
	Moon Zhang /Project Engineer	
	Eric Fu	
	Eric Fu /Reviewer	



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4 General Information

4.1 General Description of EUT

DC 5V supplied by USB port.
li-ion battery: 3.7V 1.8mW
USB Cable: 70cm unshielded
Earphone Cable: 70cm unshielded
2402MHz to 2480MHz
V4.2 Dual mode
Frequency Hopping Spread Spectrum(FHSS)
GFSK, π/4DQPSK, 8DPSK
79
Adaptive Frequency Hopping systems
Portable production
Chip Antenna
3dBi
V4.2 Dual mode
GFSK
40
Portable production
Chip Antenna
3dBi

Remark:

Model No.: IMBT25

Only the sample in section 8.1 was tested in report SZEM170900945301 & SZEM170900945302, since the electrical circuit design, layout, components used, internal wiring and functions were identical for the above model, with only the protective circuit difference.



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4.2 Test Location

All tests were performed at:

SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch

No. 1 Workshop, M-10, Middle section, Science & Technology Park, Shenzhen, Guangdong, China 518057

Telephone: +86 (0) 755 2601 2053 Fax: +86 (0) 755 2671 0594

No tests were sub-contracted.

4.3 Test Facility

The test facility is recognized, certified, or accredited by the following organizations:

· CNAS (No. CNAS L2929)

CNAS has accredited SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab to ISO/IEC 17025:2005 General Requirements for the Competence of Testing and Calibration Laboratories (CNAS-CL01 Accreditation Criteria for the Competence of Testing and Calibration Laboratories) for the competence in the field of testing.

• A2LA (Certificate No. 3816.01)

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory is accredited by the American Association for Laboratory Accreditation(A2LA). Certificate No. 3816.01.

VCCI

The 10m Semi-anechoic chamber and Shielded Room of SGS-CSTC Standards Technical Services Co., Ltd. have been registered in accordance with the Regulations for Voluntary Control Measures with Registration No.: G-823, R-4188, T-1153 and C-2383 respectively.

• FCC -Designation Number: CN1178

SGS-CSTC Standards Technical Services Co., Ltd., Shenzhen EMC Laboratory has been recognized as an accredited testing laboratory.

Designation Number: CN1178. Test Firm Registration Number: 406779.

• Industry Canada (IC)

Two 3m Semi-anechoic chambers and the 10m Semi-anechoic chamber of SGS-CSTC Standards Technical Services Co., Ltd. Shenzhen Branch EMC Lab have been registered by Certification and Engineering Bureau of Industry Canada for radio equipment testing with Registration No.: 4620C-1, 4620C-2, 4620C-3.

4.4 Deviation from Standards

None.

4.5 Abnormalities from Standard Conditions

None.

4.6 Other Information Requested by the Customer

None.



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5 SAR Evaluation

5.1 RF Exposure Compliance Requirement

5.1.1 Standard Requirement

According to KDB447498D01 General RF Exposure Guidance v06

4.3.1. Standalone SAR test exclusion considerations

Unless specifically required by the published RF exposure KDB procedures, standalone 1-g head or body and 10-g extremity SAR evaluation for general population exposure conditions, by measurement or numerical simulation, is not required when the corresponding SAR Exclusion Threshold condition, listed below, is satisfied.

5.1.2 Limits

The 1-g and 10-g SAR test exclusion thresholds for 100 MHz to 6 GHz at test separation distances ≤ 50 mm are determined by:

[(max. power of channel, including tune-up tolerance, mW)/(min. test separation distance, mm)] $\cdot [\sqrt{f(GHz)}] \le 3.0$ for 1-g SAR and ≤ 7.5 for 10-g extremity SAR, where

f(GHz) is the RF channel transmit frequency in GHz

Power and distance are rounded to the nearest mW and mm before calculation¹⁷

The result is rounded to one decimal place for comparison

The test exclusions are applicable only when the minimum test separation distance is \leq 50 mm and for transmission frequencies between 100 MHz and 6 GHz. When the minimum test separation distance is < 5 mm, a distance of 5 mm is applied to determine SAR test exclusion

5.1.3 EUT RF Exposure

For BT: the normal conducted peak power is 1.5±2dBm

The Max Conducted Peak Output Power is 3.50 dBm on the middle channel 2.441 GHz 3.50 dBm logarithmic terms convert to numeric result is nearly 2.24 mW

According to the formula. calculate the test exclusion thresholds:

[(max. power of channel, including tune-up tolerance, mW)/

(min. test separation distance, mm)] $\cdot [\sqrt{f(GHz)}]$

General RF Exposure = $(2.24 \text{ mW} / 5 \text{ mm}) \times \sqrt{2.441 \text{ GHz}} = 0.70$ (1)

SAR requirement:

 $S = 3.0 \tag{2}$

(1) < (2)

So the SAR report is not required.



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(1)

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For BLE:the normal conducted peak power is -2.0 ± 2 dBm

The Max Conducted Peak Output Power is 0.00 dBm on the middle channel 2.44 GHz 0.00 dBm logarithmic terms convert to numeric result is nearly 1.00 mW

According to the formula. calculate the test exclusion thresholds:

[(max. power of channel, including tune-up tolerance, mW)/

(min. test separation distance, mm)] · [√f(GHz)]

General RF Exposure = $(1.00 \text{ mW} / 5 \text{ mm}) \text{ x} \sqrt{2.44 \text{ GHz}} = 0.31$

SAR requirement:

 $S = 3.0 \tag{2}$

(1) < (2)

So the SAR report is not required.